

Test Report

Applicant : Telink Semiconductor (Shanghai) Co., Ltd.
Address : Bldg 3, No. 1500, Zuchongzhi Rd, Zhangjiang
Hi-tech Park, Shanghai, China.
Product Name : TLSR8208EDK56D
Brand Mark : TELINK
Model : TLSR8208EDK56D
FCC ID : OEOTLSR8208EDK56D
Report Number : BLA-EMC-202404-A4902
Date of Receipt : 2024.04.18
Date of Test : 2024.04.18 to 2024.04.26
Test Standard : 47 CFR Part 15, Subpart C 15.247
Test Result : Pass

Compiled by: *Hugh*Review by: *Sueels*Approved by: *Blue Zheng*

Issued Date: 2024.04.26

BlueAsia of Technical Services(Shenzhen) Co.,Ltd.Address: Building C, No. 107, Shihuan Road, Shiyuan Sub-District, Baoan District,
Shenzhen, Guangdong Province, China

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Revise Record

Version No.	Date	Description
01	2024.04.26	Original

BlueAsia

1 General information

1.1 General information

Applicant	Telink Semiconductor (Shanghai) Co., Ltd.
Address	Bldg 3, No. 1500, Zuchongzhi Rd, Zhangjiang Hi-tech Park, Shanghai, China.
Manufacturer	Telink Semiconductor (Shanghai) Co., Ltd.
Address	Bldg 3, No. 1500, Zuchongzhi Rd, Zhangjiang Hi-tech Park, Shanghai, China.
Factory	Telink Semiconductor (Shanghai) Co., Ltd.
Address	Bldg 3, No. 1500, Zuchongzhi Rd, Zhangjiang Hi-tech Park, Shanghai, China.

1.2 General description of EUT

Product Name:	TLSR8208EDK56D
Model No.:	TLSR8208EDK56D
Series model:	N/A
Operation Frequency:	2402MHz-2480MHz
Modulation Type:	GFSK
Rate data:	1Mbps; 2Mbps
Channel Spacing:	2MHz
Number of Channels:	40
Antenna Type:	PCB antenna
Antenna Gain:	3dBi(Provided by customer)
Power supply:	DC3.3V
Hardware version:	V1.0
Software version:	V0001

Note: For a more detailed description, please refer to Specification or User's Manual supplied by the applicant and/or manufacturer.

2 Test summary

No.	Test item	Result	Remark
1	Antenna Requirement	Pass	
2	Conducted Emissions at AC Power Line (150kHz-30MHz)	Pass	
3	Conducted Peak Output Power	Pass	
4	Minimum 6dB Bandwidth	Pass	
5	Power Spectrum Density	Pass	
6	Conducted Band Edges Measurement	Pass	
7	Conducted Spurious Emissions	Pass	
8	Radiated Spurious Emissions	Pass	
9	Radiated Emissions which fall in the restricted bands	Pass	

3 Test Configuration

3.1 Test mode

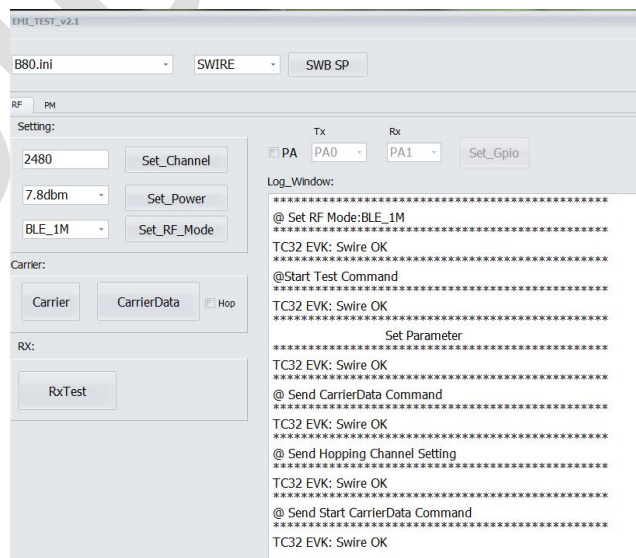
Test Mode ^{Note 1}	Description
TX	Keep the EUT in continuously transmitting with modulation mode.
RX	Keep the EUT in receiving mode
TX Low channel	Keep the EUT in continuously transmitting mode in low channel
TX middle channel	Keep the EUT in continuously transmitting mode in middle channel
TX high channel	Keep the EUT in continuously transmitting mode in high channel

Note 1: The EUT was configured to measure its highest possible emission and/or immunity level. The test modes were adapted according to the operation manual for use; the EUT was operated in the engineering mode ^{Note 2} to fix the TX or Rx frequency that was for the purpose of the measurements.

Note 2: Special software is used. The software provided by client to enable the EUT under transmission condition continuously at specific channel frequencies individually.

Power level setup in software			
Test Software Name	EMI_TEST		
Mode	Channel	Frequency (MHz)	Soft Set
GFSK	CH00	2402	TX level : 7.8
	CH39	2442	
	CH78	2480	

Run Software



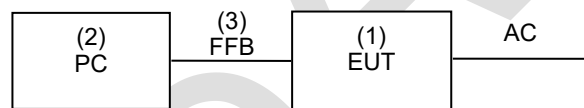
Operation Frequency each of channel

Channel	Frequency	Channel	Frequency	Channel	Frequency	Channel	Frequency
1	2402MHz	11	2422MHz	21	2442MHz	31	2462MHz
2	2404MHz	12	2424MHz	22	2444MHz	32	2464MHz
...
9	2418MHz	19	2438MHz	29	2458MHz	39	2478MHz
10	2420MHz	20	2440MHz	30	2460MHz	40	2480MHz

3.2 Test channel

Channel	Frequency
The lowest channel	2402MHz
The middle channel	2442MHz
The Highest channel	2480MHz

3.3 Configuration diagram of EUT



Support equipment

Name	Device type	Brand	Mode	Series No	Remark
(1)	Active subwoofer system	SHARP/VTREK	CP-SW192	N/A	EUT
(2)	PC	Lenovo	E460C	N/A	N/A
(3)	Fixed frequency board	N/A	N/A	N/A	N/A

Note: See test photographs attached in APPENDIX A for the actual connections between Product and support equipment.

3.4 Auxiliary equipment

Device Type	Manufacturer	Model Name	Serial No.	Remark
PC	HASEE	N/A	N/A	N/A

Note:

“--” mean no any auxiliary device during testing.

3.5 Test environment

Environment	Temperature	Voltage
Normal	25°C	DC 3.3V

4 Laboratory information

4.1 Laboratory and accreditations

The test facility is recognized, certified, or accredited by the following organizations:

Company name:	BlueAsia of Technical Services(Shenzhen) Co., Ltd.
Address:	Building C, No. 107, Shihuan Road, Shiyan Sub-District, Baoan District, Shenzhen, Guangdong Province, China
CNAS accredited No.:	L9788
A2LA Cert. No.:	5071.01
FCC Designation No.:	CN1252
ISED CAB identifier No.:	CN0028
Telephone:	+86-755-28682673
FAX:	+86-755-28682673

4.2 Measurement uncertainty

This uncertainty represents an expanded uncertainty expressed at approximately the 95% confidence level using a coverage factor of $k=1.96$.

Parameter	Expanded Uncertainty
Radiated Emission(9kHz-30MHz)	± 4.34 dB
Radiated Emission(30Mz-1000MHz)	± 4.24 dB
Radiated Emission(1GHz-18GHz)	± 4.68 dB
AC Power Line Conducted Emission(150kHz-30MHz)	± 3.45 dB
Occupied Channel Bandwidth	± 5 %
RF output power, conducted	± 1.5 dB
Power Spectral Density, conducted	± 3.0 dB
Unwanted Emissions, conducted	± 3.0 dB
Temperature	± 3 °C
Supply voltages	± 3 %
Time	± 5 %

5 Test equipment

Equipment No.	Equipment Name	Model No.	Manufacture	S/N	Cal. Date	Next Cal. Date
BLA-EMC-008	Spectrum	FSP40	R&S	100817	2023/08/30	2024/08/29
BLA-EMC-009	EMI Receiver	ESR7	R&S	101199	2023/08/30	2024/08/29
BLA-EMC-012	broad band Antenna	VULB9168	Schwarz beck	00836 P:00227	2022/10/12	2025/10/11
BLA-EMC-013	Horn Antenna	BBHA9120D	Schwarz beck	01892	2022/09/13	2025/09/12
BLA-EMC-014	Amplifier	PA_000318G-45	SKET	PA2018043003	2023/08/30	2024/08/29
BLA-EMC-016	Signal Generator	N5182A	Agilent	MY52420567	2023/11/16	2024/11/15
BLA-EMC-028	Spectrum	N9020A	Agilent	MY53420839	2023/11/16	2024/11/15
BLA-EMC-038	Spectrum	N9020A	Agilent	MY49100060	2023/08/30	2024/08/29
BLA-EMC-042	Power sensor	RPR3006W	DARE	14I00889SN042	2023/09/01	2024/08/31
BLA-EMC-043	Loop antenna	FMZB1519B	SCHNARZBECK	00102	2022/09/14	2025/09/13
BLA-EMC-044	Wideband radio communication tester	CMW500	R&S	132429	2023/08/30	2024/08/29
BLA-EMC-046	Filter bank	2.4G/5G Filter bank	SKET	N/A	2023/07/07	2024/07/06
BLA-EMC-061	Receiver	ESPI7	R&S	101477	2023/07/07	2024/07/06
BLA-EMC-062	Signal Generator	N5181A	Agilent	MY46240904	2023/07/07	2024/07/06
BLA-EMC-064	Signal Generator	N5182B	KEYSIGHT	MY58108892	2023/07/07	2024/07/06
BLA-EMC-065	broadband Antenna	VULB9168	Schwarz beck	01065P	2022/12/12	2025/12/11
BLA-EMC-066	Amplifier	LNPA_30M01G-30	SKET	SK2021060801	2023/07/07	2024/07/06
BLA-EMC-079	Spectrum	N9020A	Agilent	MY54420161	2023/08/30	2024/08/29
BLA-EMC-080	Signal Generator	N5182A	Agilent	MY47420955	2023/08/30	2024/08/29
BLA-EMC-086	Amplifier	LNPA_18G40G-50dB	SKET	SK2022071301	2023/08/14	2024/08/13

6 Test result

6.1 Antenna requirement

Test Standard	47 CFR Part 15, Subpart C 15.247
Test Method	N/A

6.1.1 Requirement

An intentional radiator shall be designed to ensure that no antenna other than that furnished by the responsible party shall be used with the device. The use of an antenna that uses a unique coupling to the intentional radiator, the manufacturer may design the unit permanently attached antenna or of a so that a broken antenna can be replaced by the user, but the use of a standard antenna jack or electrical connector is prohibited.

EUT antenna:

The antenna is integrated on the main PCB and no consideration of replacement. The best case gain of the antenna is 3 dBi.

6.2 Conducted emissions at AC power line (150 kHz-30 MHz)

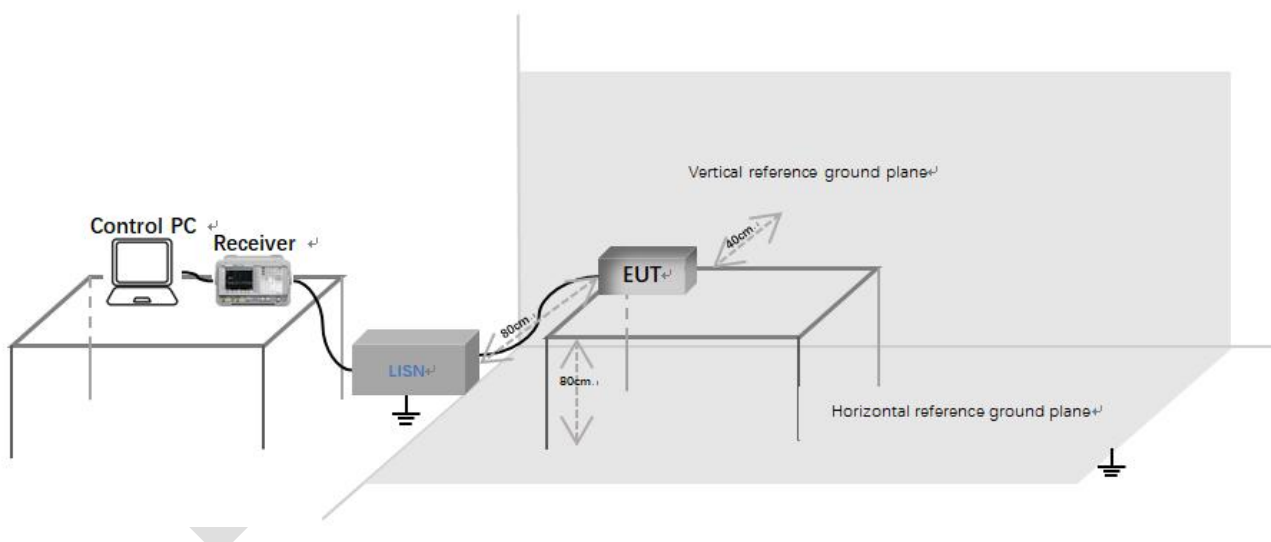
Test Standard	47 CFR Part 15, Subpart C 15.247
Test Method	ANSI C63.10 (2013) Section 6.2
Test Mode (Pre-Scan)	TX
Test Mode (Final Test)	TX

6.2.1 Limit

Frequency of emission(MHz)	Conducted limit(dB μ V)	
	Quasi-peak	Average
0.15-0.5	66 to 56*	56 to 46*
0.5-5	56	46
5-30	60	50

*Decreases with the logarithm of the frequency.

6.2.2 Test setup



Description of test setup connection:

- Connect the control PC to the receiver through a USB to GPIB cable;
- The receiver is connected to the LISN through a coaxial line;
- Connect the power port of LISN to the EUT.

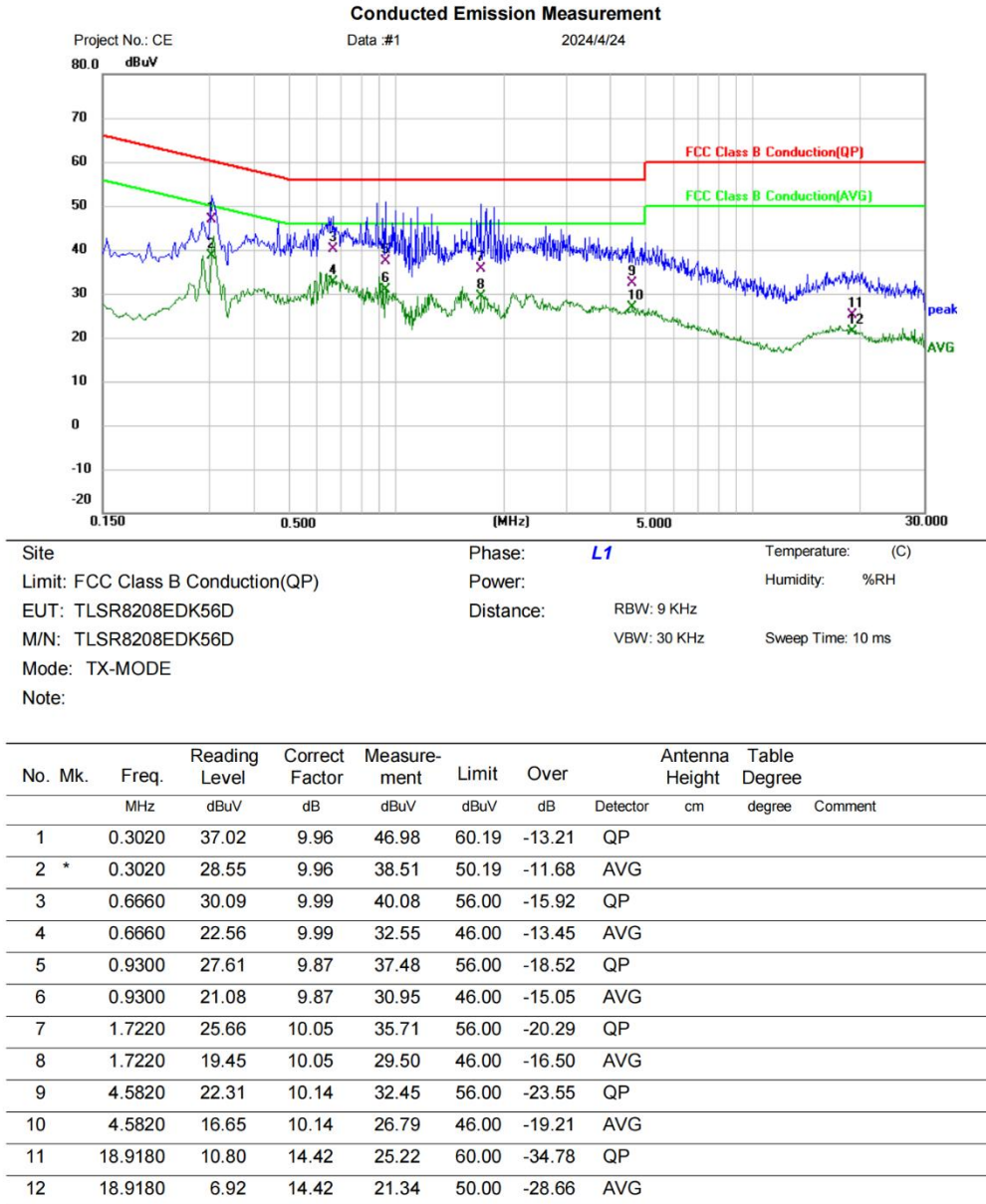
6.2.3 Procedure

- 1) The mains terminal disturbance voltage test was conducted in a shielded room.
- 2) The EUT was connected to AC power source through a LISN 1 (Line Impedance Stabilization Network) which provides a 50ohm/50H + 5ohm linear impedance. The power cables of all other units of the EUT were connected to a second LISN 2, which was bonded to the ground reference plane in the same way as the LISN 1 for the unit being measured. A multiple socket outlet strip was used to connect multiple power cables to a single LISN provided the rating of the LISN was not exceeded.
- 3) The tabletop EUT was placed upon a non-metallic table 0.8m above the ground reference plane. And for floor-standing arrangement, the EUT was placed on the horizontal ground reference plane,
- 4) The test was performed with a vertical ground reference plane. The rear of the EUT shall be 0.4 m from the vertical ground reference plane. The vertical ground reference plane was bonded to the horizontal ground reference plane. The LISN 1 was placed 0.8 m from the boundary of the unit under test and bonded to a ground reference plane for LISNs mounted on top of the ground reference plane. This distance was between the closest points of the LISN 1 and the EUT. All other units of the EUT and associated equipment was at least 0.8 m from the LISN 2.
- 5) In order to find the maximum emission, the relative positions of equipment and all of the interface cables must be changed according to ANSI C63.10 on conducted measurement.

LISN=Read Level+ Cable Loss+ LISN Factor

6.2.4 Test data

[Test mode: TX]; [Line: Line];[Power:AC120V/60Hz]


Test Result: Pass

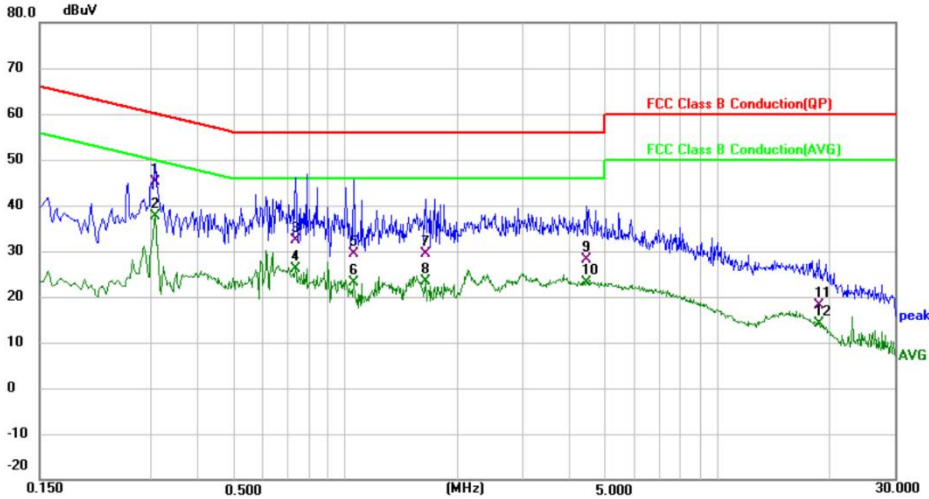
[Test mode: TX]; [Line: Neutral];[Power:AC120V/60Hz]

Conducted Emission Measurement

Project No.: CE

Data :#2

2024/4/24



Site	Phase: N	Temperature: (C)
Limit: FCC Class B Conduction(QP)	Power:	Humidity: %RH
EUT: TLSR8208EDK56D	Distance:	RBW: 9 KHz
M/N: TLSR8208EDK56D		VBW: 30 KHz
Mode: TX-MODE		Sweep Time: 10 ms
Note:		

No.	Mk.	Freq.	Reading Level	Correct Factor	Measurement	Limit	Over	Antenna Height	Table Degree	
		MHz	dBuV	dB	dBuV	dBuV	dB	cm	degree	Comment
1		0.3060	35.08	9.93	45.01	60.08	-15.07	QP		
2	*	0.3060	27.68	9.93	37.61	50.08	-12.47	AVG		
3		0.7340	22.44	9.95	32.39	56.00	-23.61	QP		
4		0.7340	16.10	9.95	26.05	46.00	-19.95	AVG		
5		1.0500	19.53	9.87	29.40	56.00	-26.60	QP		
6		1.0500	13.26	9.87	23.13	46.00	-22.87	AVG		
7		1.6420	19.32	9.96	29.28	56.00	-26.72	QP		
8		1.6420	13.36	9.96	23.32	46.00	-22.68	AVG		
9		4.4380	17.85	10.18	28.03	56.00	-27.97	QP		
10		4.4380	13.00	10.18	23.18	46.00	-22.82	AVG		
11		18.7860	3.95	14.26	18.21	60.00	-41.79	QP		
12		18.7860	-0.09	14.26	14.17	50.00	-35.83	AVG		

Test Result: Pass

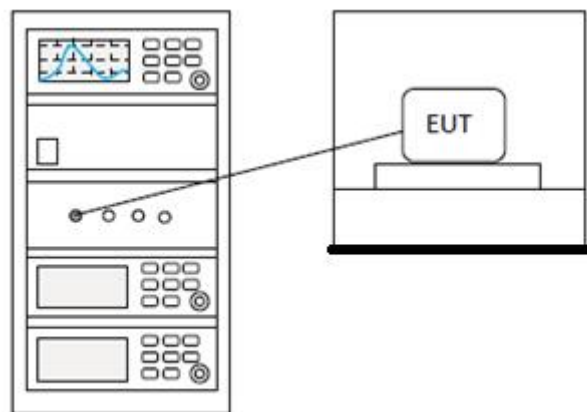
6.3 Conducted peak output Power

Test Standard	47 CFR Part 15, Subpart C 15.247
Test Method	ANSI C63.10 (2013) Section 7.8.5
Test Mode (Pre-Scan)	TX
Test Mode (Final Test)	TX

6.3.1 Limit

Frequency range(MHz)	Output power of the intentional radiator(watt)
902-928	1 for ≥ 50 hopping channels
	0.25 for $25 \leq$ hopping channels < 50
	1 for digital modulation
2400-2483.5	1 for ≥ 75 non-overlapping hopping channels
	0.125 for all other frequency hopping systems
	1 for digital modulation
5725-5850	1 for frequency hopping systems and digital modulation

6.3.2 Test setup



6.3.3 Test data

Pass: Please refer to appendix A for details

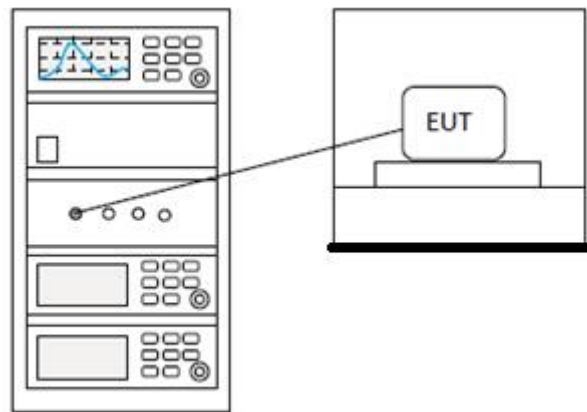
6.4 Minimum 6dB bandwidth

Test Standard	47 CFR Part 15, Subpart C 15.247
Test Method	ANSI C63.10 (2013) Section 11.8.1
Test Mode (Pre-Scan)	TX
Test Mode (Final Test)	TX

6.4.1 Limit

≥500 kHz

6.4.2 Test setup



6.4.3 Test data

Pass: Please refer to appendix A for details

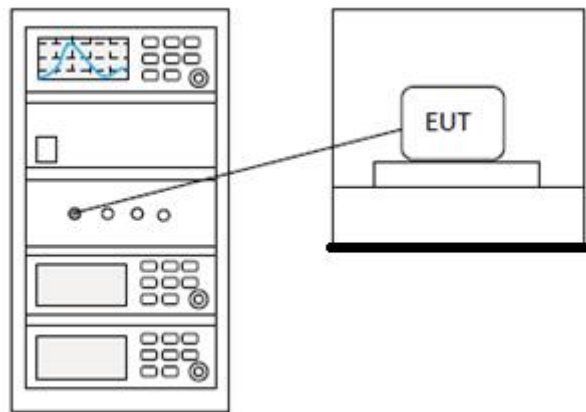
6.5 Power spectrum density

Test Standard	47 CFR Part 15, Subpart C 15.247
Test Method	ANSI C63.10 (2013) Section 11.10.2
Test Mode (Pre-Scan)	TX
Test Mode (Final Test)	TX

6.5.1 Limit

≤8dBm in any 3 kHz band during any time interval of continuous transmission

6.5.2 Test setup



6.5.3 Test data

Pass: Please refer to appendix A for details

6.6 Conducted Band Edges Measurement

Test Standard	47 CFR Part 15, Subpart C 15.247
Test Method	ANSI C63.10 (2013) Section 7.8.8 & Section 11.13.3.2
Test Mode (Pre-Scan)	TX
Test Mode (Final Test)	TX

6.6.1 Limit

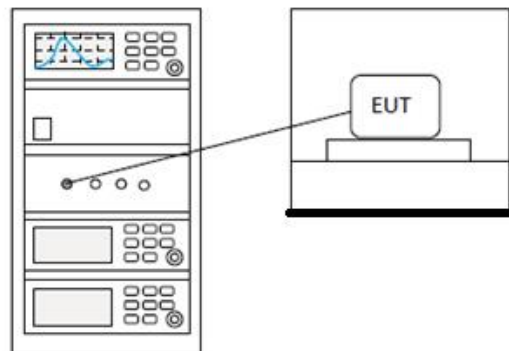
In any 100 kHz bandwidth outside the frequency band in which the spread spectrum or digitally modulated intentional radiator is operating, the radio frequency power that is produced by the intentional radiator shall be at least 20 dB below that in the 100 kHz bandwidth within the band that contains the highest level of the desired power, based on either an RF conducted or a radiated measurement, provided the transmitter demonstrates compliance with the peak conducted power limits.

If the transmitter complies with the conducted power limits based on the use of RMS averaging over a time interval, as permitted under paragraph (b)(3) of this section, the attenuation required under this paragraph shall be 30 dB instead of 20dB.

Attenuation below the general limits specified in §15.209(a) is not required.

In addition, radiated emissions which fall in the restricted bands, as defined in §15.205(a), must also comply with the radiated emission limits specified in §15.209(a) (see §15.205(c)).

6.6.2 Test setup



6.6.3 Test data

Pass: Please refer to appendix A for details

6.7 Conducted spurious emissions

Test Standard	47 CFR Part 15, Subpart C 15.247
Test Method	ANSI C63.10 (2013) Section 7.8.6 & Section 11.11
Test Mode (Pre-Scan)	TX
Test Mode (Final Test)	TX

6.7.1 Limit

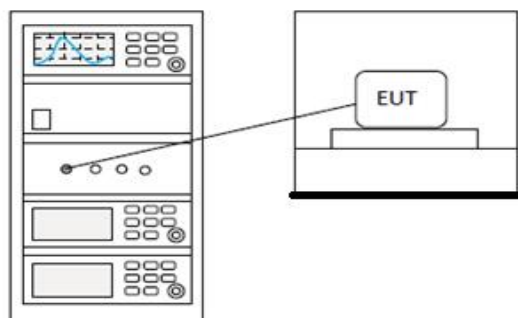
In any 100 kHz bandwidth outside the frequency band in which the spread spectrum or digitally modulated intentional radiator is operating, the radio frequency power that is produced by the intentional radiator shall be at least 20 dB below that in the 100 kHz bandwidth within the band that contains the highest level of the desired power, based on either an RF conducted or a radiated measurement, provided the transmitter demonstrates compliance with the peak conducted power limits.

If the transmitter complies with the conducted power limits based on the use of RMS averaging over a time interval, as permitted under paragraph (b)(3) of this section, the attenuation required under this paragraph shall be 30 dB instead of 20dB.

Attenuation below the general limits specified in §15.209(a) is not required.

In addition, radiated emissions which fall in the restricted bands, as defined in §15.205(a), must also comply with the radiated emission limits specified in §15.209(a) (see §15.205(c)).

6.7.2 Test setup



6.7.3 Test data

Pass: Please refer to appendix A for details

6.8 Radiated spurious emissions

Test Standard	47 CFR Part 15, Subpart C 15.247
Test Method	ANSI C63.10 (2013) Section 6.4,6.5,6.6
Test Mode (Pre-Scan)	TX
Test Mode (Final Test)	TX

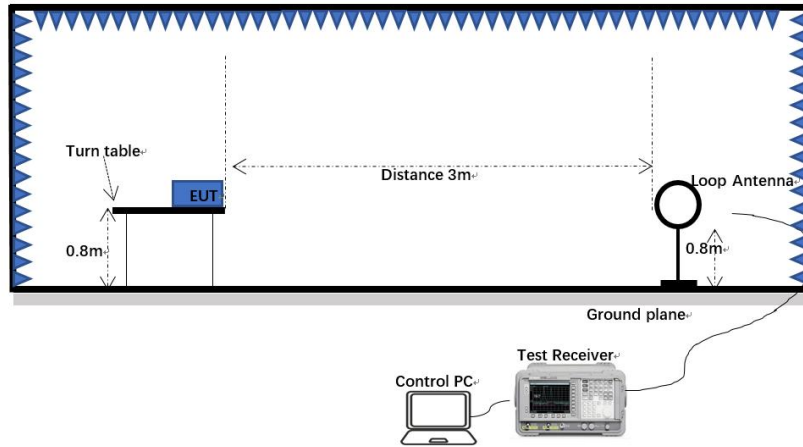
6.8.1 Limit

Frequency(MHz)	Field strength(microvolts/meter)	Measurement distance(meters)
0.009-0.490	2400/F(kHz)	300
0.490-1.705	24000/F(kHz)	30
1.705-30.0	30	30
30-88	100	3
88-216	150	3
216-960	200	3
Above 960	500	3

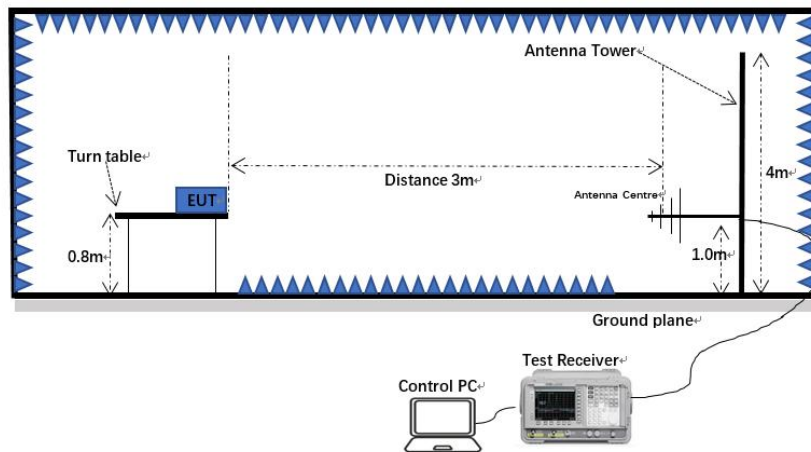
Remark: The emission limits shown in the above table are based on measurements employing a CISPR quasi-peak detector except for the frequency bands 9-90kHz, 110-490kHz and above 1000MHz. Radiated emission limits in these three bands are based on measurements employing an average detector, the peak field strength of any emission shall not exceed the maximum permitted average limits specified above by more than 20 dB under any condition of modulation.

6.8.2 Test setup

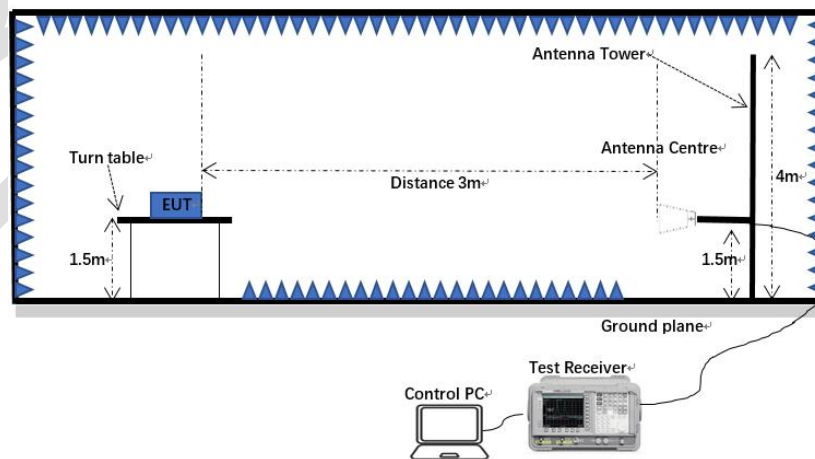
Below 1GHz:



30MHz-1GHz:



Above 1GHz:



6.8.3 Procedure

- a) For below 1GHz, the EUT was placed on the top of a rotating table 0.8 meters above the ground at a 3 or 10 meter semi-anechoic chamber. The table was rotated 360 degrees to determine the position of the highest radiation.
- b) For above 1GHz, the EUT was placed on the top of a rotating table 1.5 meters above the ground at a 3 meter fully-anechoic chamber. The table was rotated 360 degrees to determine the position of the highest radiation.
- c) The EUT was set 3 or 10 meters away from the interference-receiving antenna, which was mounted on the top of a variable-height antenna tower.
- d) The antenna height is varied from one meter to four meters above the ground to determine the maximum value of the field strength. Both horizontal and vertical polarizations of the antenna are set to make the measurement.
- e) For each suspected emission, the EUT was arranged to its worst case and then the antenna was tuned to heights from 1 meter to 4 meters (for the test frequency of below 30MHz, the antenna was tuned to heights 1 meter) and the rotatable table was turned from 0 degrees to 360 degrees to find the maximum reading.
- f) The test-receiver system was set to Peak Detect Function and Specified Bandwidth with Maximum Hold Mode.
- g) If the emission level of the EUT in peak mode was 10dB lower than the limit specified, then testing could be stopped and the peak values of the EUT would be reported. Otherwise the emissions that did not have 10dB margin would be re-tested one by one using peak, quasi-peak or average method as specified and then reported in a data sheet.
- h) Test the EUT in the lowest channel, the middle channel, the highest channel.
- i) The radiation measurements are performed in X, Y, Z axis positioning for Transmitting mode, and found the X axis positioning which it is the worst case.
- j) Repeat above procedures until all frequencies measured was complete.

Note 1: Scan from 9 kHz to 25GHz, the disturbance above 12.75GHz and below 30MHz was very low. The points marked on above plots are the highest emissions could be found when testing, so only above points had been displayed. The amplitude of spurious emissions from the radiator which are attenuated more than 20dB below the limit need not be reported. Fundamental frequency is blocked by filter, and only spurious emission is shown.

Note 2: For frequencies above 1GHz, the field strength limits are based on average limits. However, the peak field strength of any emission shall not exceed the maximum permitted average limits specified above by more than 20 dB under any condition of modulation. For the emissions whose peak level is lower than the average limit, only the peak measurement is shown in the report.

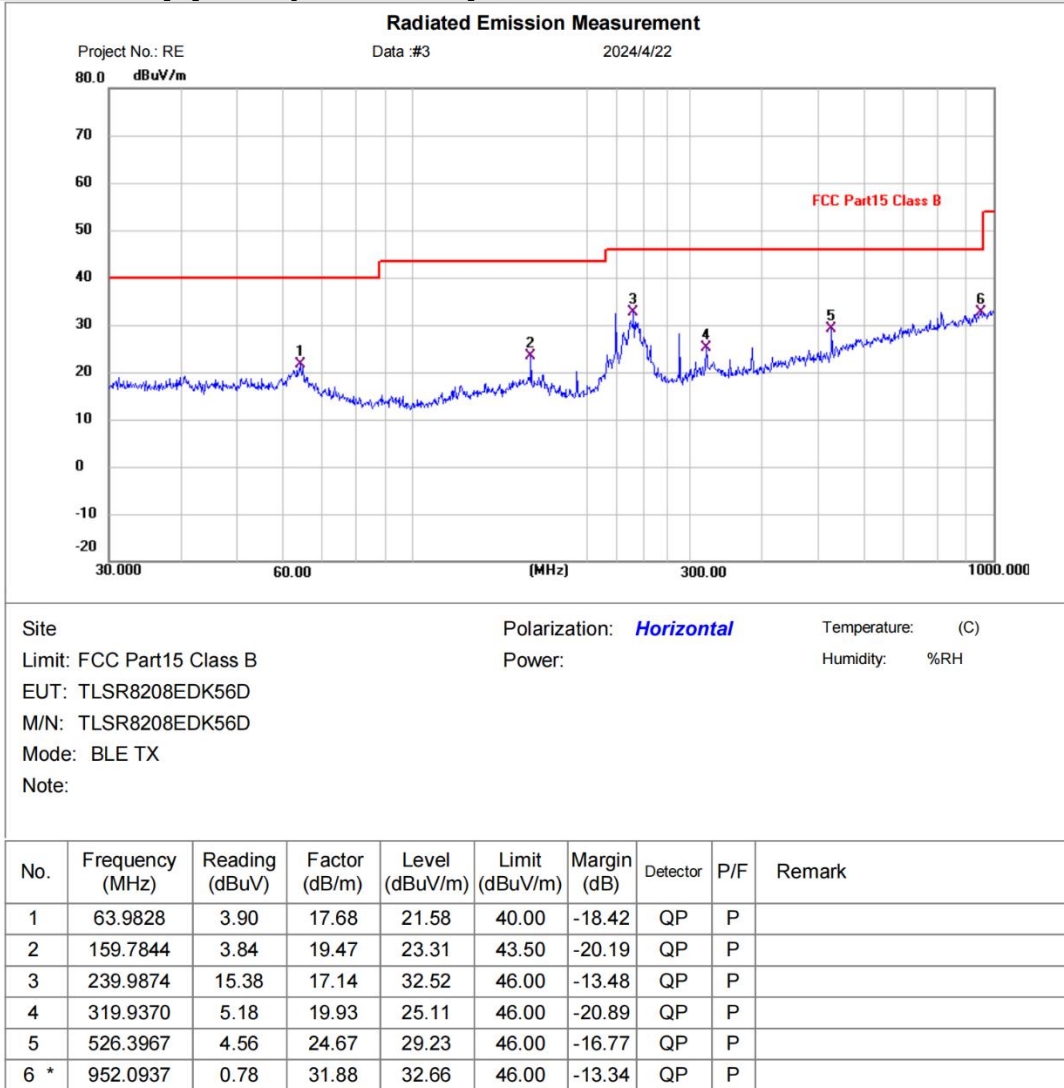
Note 3: The field strength is calculated by adding the Antenna Factor, Cable Factor & Preamplifier. The basic equation with a sample calculation is as follows:

$$\text{Level (dBuV)} = \text{Reading (dBuV)} + \text{Factor (dB/m)}$$

6.8.4 Test data

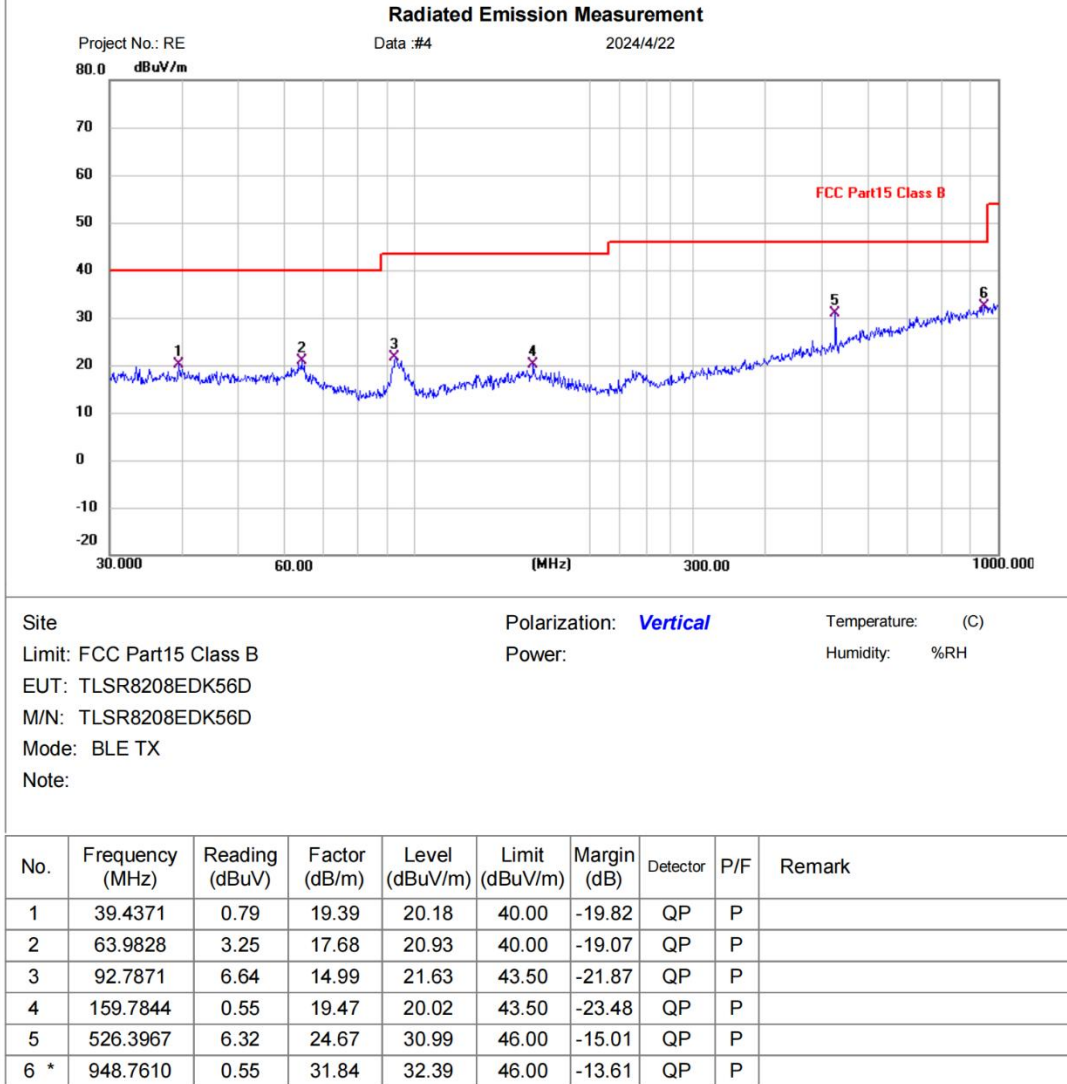
Below 1GHz

[Test mode: TX]; [Polarity: Horizontal]



Test Result: Pass

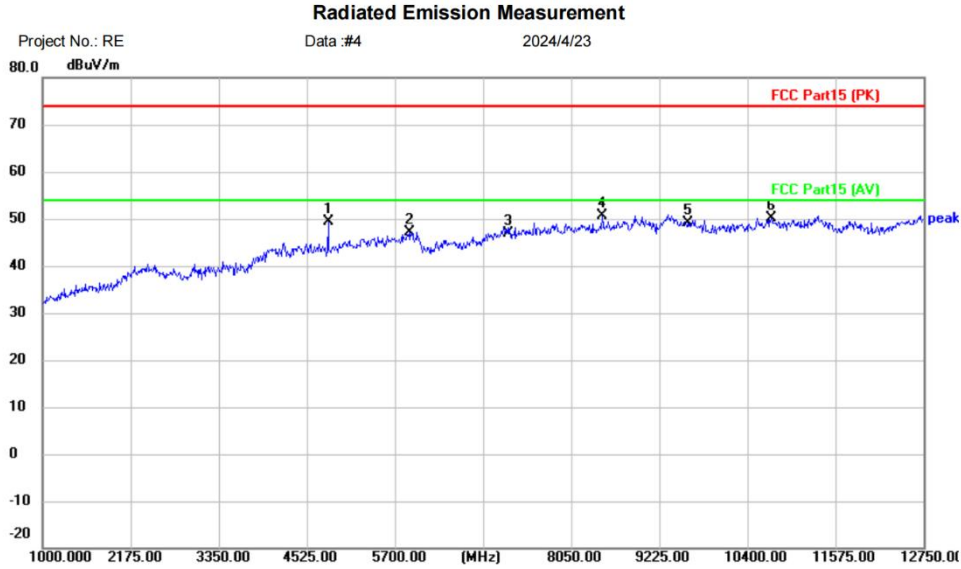
[Test mode: TX]; [Polarity: Vertical]


Test Result: Pass

Above 1GHz:

Remark: During the test, pre-scan the BLE1M/BLE2M mode, and found the BLE1M mode which it is worse case.

[Test mode: TX low channel]; [Polarity: Horizontal]



Project No.: RE Data: #4 2024/4/23

Site: Polarization: **Horizontal** Temperature: (C)

Limit: FCC Part15 (PK) Power: Humidity: %RH

EUT: TLSR8208EDK56D

M/N: TLSR8208EDK56D

Mode: BLE 1M TX 2402

Note:

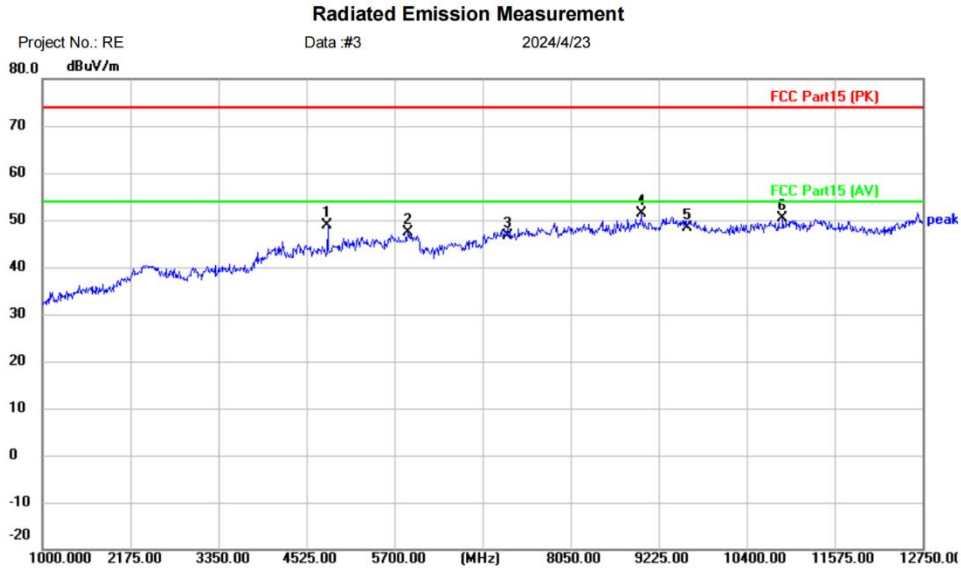
No.	Mk.	Freq. MHz	Reading Level dBuV	Correct Factor dB	Measurement dBuV/m	Limit dBuV/m	Over dB	Detector	Comment
1		4807.000	43.79	5.64	49.43	74.00	-24.57	peak	
2		5888.000	38.44	8.60	47.04	74.00	-26.96	peak	
3		7206.000	37.62	9.24	46.86	74.00	-27.14	peak	
4	*	8461.250	40.02	10.70	50.72	74.00	-23.28	peak	
5		9608.000	36.81	12.31	49.12	74.00	-24.88	peak	
6		10717.25	37.08	13.08	50.16	74.00	-23.84	peak	

*:Maximum data x:Over limit !:over margin

<Reference Only

Test Result: Pass

[Test mode: TX low channel]; [Polarity: Vertical]



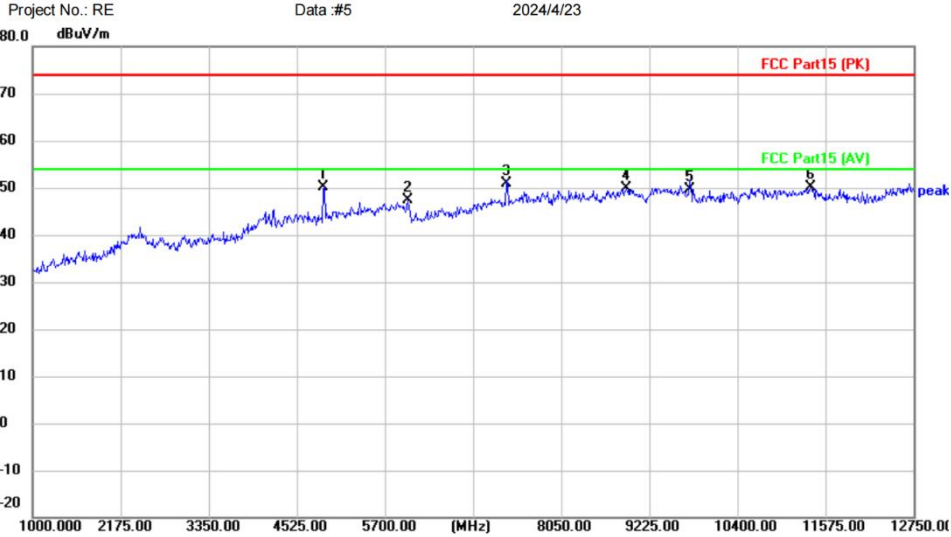
Site: Polarization: **Vertical** Temperature: (C)
 Limit: FCC Part15 (PK) Power: Humidity: %RH
 EUT: TLSR8208EDK56D
 M/N: TLSR8208EDK56D
 Mode: BLE 1M TX 2402
 Note:

No.	Mk.	Freq. MHz	Reading Level dBuV	Correct Factor dB	Measure- ment dBuV/m	Limit dBuV/m	Over dB	Detector	Comment
1		4806.000	43.22	5.64	48.86	74.00	-25.14	peak	
2		5876.250	38.72	8.54	47.26	74.00	-26.74	peak	
3		7206.000	37.38	9.24	46.62	74.00	-27.38	peak	
4	*	8990.000	39.00	12.42	51.42	74.00	-22.58	peak	
5		9608.000	36.02	12.31	48.33	74.00	-25.67	peak	
6		10881.75	37.33	13.05	50.38	74.00	-23.62	peak	

Test Result: Pass

[Test mode: TX middle channel]; [Polarity: Horizontal]

Radiated Emission Measurement



Site: Polarization: **Horizontal** Temperature: (C)
 Limit: FCC Part15 (PK) Power: Humidity: %RH
 EUT: TLSR8208EDK56D
 M/N: TLSR8208EDK56D
 Mode: BLE 1M TX 2442
 Note:

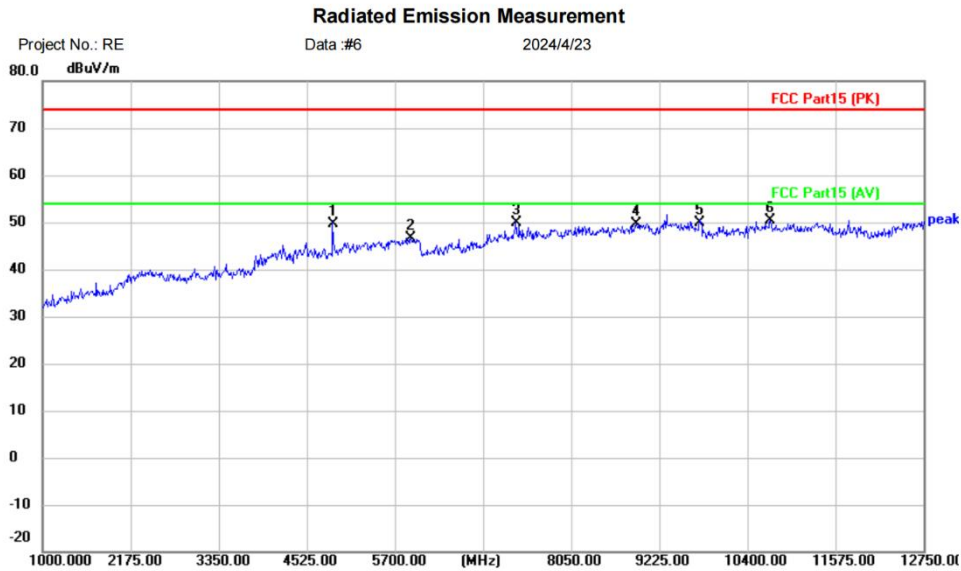
No.	Mk.	Freq. MHz	Reading Level dBuV	Correct Factor dB	Measure- ment dBuV/m	Limit dBuV/m	Over dB	Detector	Comment
1		4884.000	44.43	5.75	50.18	74.00	-23.82	peak	
2		6005.500	41.81	5.61	47.42	74.00	-26.58	peak	
3	*	7326.000	41.36	9.43	50.79	74.00	-23.21	peak	
4		8919.500	37.76	12.14	49.90	74.00	-24.10	peak	
5		9768.000	37.29	12.22	49.51	74.00	-24.49	peak	
6		11375.25	37.50	12.63	50.13	74.00	-23.87	peak	

*:Maximum data x:Over limit !:over margin

⟨Reference Only

Test Result: Pass

[Test mode: TX middle channel]; [Polarity: Vertical]



Site: _____ Polarization: **Vertical** Temperature: (C)
 Limit: FCC Part15 (PK) Power: _____ Humidity: %RH
 EUT: TLSR8208EDK56D
 M/N: TLSR8208EDK56D
 Mode: BLE 1M TX 2442
 Note: _____

No.	Mk.	Freq.	Reading	Correct	Measure-	Limit	Over		
		MHz	Level	Factor	ment			Detector	Comment
			dBuV	dB	dBuV/m	dBuV/m	dB		
1		4884.000	44.00	5.75	49.75	74.00	-24.25	peak	
2		5911.500	38.07	8.68	46.75	74.00	-27.25	peak	
3		7326.000	40.53	9.43	49.96	74.00	-24.04	peak	
4		8919.500	37.51	12.14	49.65	74.00	-24.35	peak	
5		9768.000	37.58	12.22	49.80	74.00	-24.20	peak	
6	*	10705.50	37.36	13.12	50.48	74.00	-23.52	peak	

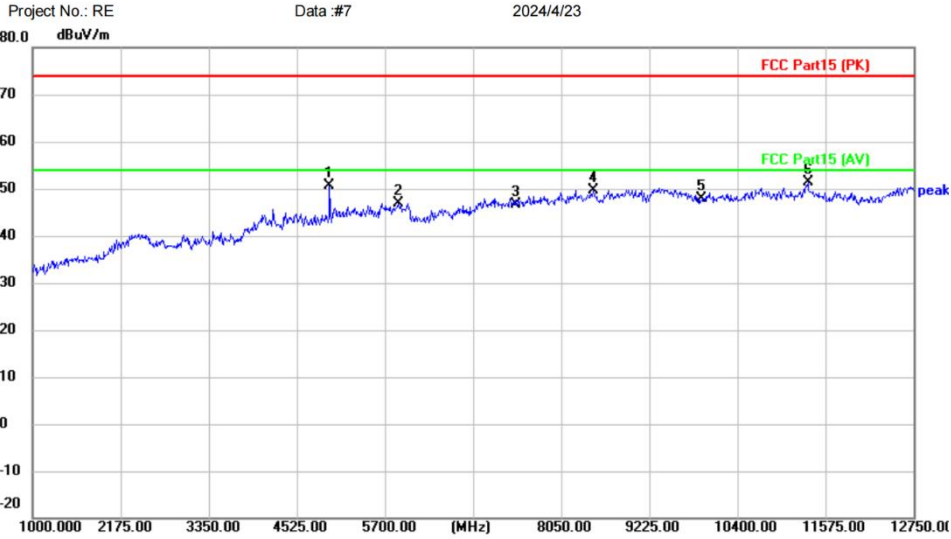
*:Maximum data x:Over limit !:over margin

<Reference Only

Test Result: Pass

[Test mode: TX High channel]; [Polarity: Horizontal]

Radiated Emission Measurement



Site: Polarization: **Horizontal** Temperature: (C)
 Limit: FCC Part15 (PK) Power: Humidity: %RH
 EUT: TLSR8208EDK56D
 M/N: TLSR8208EDK56D
 Mode: BLE 1M TX 2480
 Note:

No.	Mk.	Freq. MHz	Reading Level dBuV	Correct Factor dB	Measure- ment dBuV/m	Limit dBuV/m	Over dB	Detector	Comment
1		4959.750	44.04	6.60	50.64	74.00	-23.36	peak	
2		5876.250	38.42	8.54	46.96	74.00	-27.04	peak	
3		7440.000	37.07	9.64	46.71	74.00	-27.29	peak	
4		8473.000	38.94	10.77	49.71	74.00	-24.29	peak	
5		9920.000	35.63	12.14	47.77	74.00	-26.23	peak	
6	*	11340.00	38.71	12.67	51.38	74.00	-22.62	peak	

*:Maximum data x:Over limit !:over margin

<Reference Only

Test Result: Pass